Notice of References Cited Application/Control No. 10/559,793 Examiner Dimple N. Bodawala Applicant(s)/Patent Under Reexamination KOBAYASHI ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A.	US-4,208,879 A	06-1980	Segawa, Kazuyoshi	60/547.1
*	В	US-5,533,336 A	07-1996	Kiat et al.	60/533
*	С	US-5,630,316 A	05-1997	Itsuji et al.	60/418
*	D	US-5,688,535 A	11-1997	Koda et al.	425/145
*	E	US-5,747,076 A	05-1998	Jaroschek et al.	425/145
*	F	US-6,120,711 A	09-2000	Takizawa, Michiaki	264/40.1
*	G	US-6,183,682 B1	02-2001	Shimizu et al.	264/328.1
*	Н	US-6,289,259 B1	09-2001	Choi et al.	700/197
*	1	US-2002/0053204 A1	05-2002	KOGANE et al.	60/327
*	J	US-6,868,305 B2	03-2005	Choi et al.	700/200
*	К	US-2005/0186299 A1	08-2005	Berger et al.	425/072.1
*	L	US-7,067,078 B2	06-2006	Amano, Mitsuaki	264/40.1
*	М	US-7,100,631 B2	09-2006	Liu et al.	137/208

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

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